



Advances in Nondestructive Testing and Evaluation

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Deadline for manuscript
submissions:

closed (20 February 2024)

Message from the Guest Editors

Dear Colleagues,

The purpose of this special issue is to shed light on recent advances in the field of non-destructive testing and evaluation, including novel and emerging approaches for non-destructive testing and evaluation, inverse problem evaluation, and pioneering applications for a vast array of industries and laboratories.

Owing to the requirement for technical breakthrough in the field of non-destructive testing and evaluation, numerous endeavors are being undertaken, including but not limited to:

- (1) Materials characterization;
- (2) Innovation application and methodologies in the field of NDT;
- (3) Evaluation using inverse problem;
- (4) Integration of test methods using conventional NDT&E methods;
- (5) Ultra-precise sensor (sensitivity and resolution) development using advanced technology in electrical and electronic fields;
- (6) Ultra-fast inspection (real-time NDT and high-speed flaw recognition);
- (7) Automation of the inspection process (applying robot technology);





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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